

### Information Disclosure Statement by Applicant

Application Number: 10/675046  
 Filing Date: 08/29/2003  
 First Named Inventor: Hsu  
 Group Art Unit: NA  
 Examiner: NA  
 Atty. Docket Num. HSJ920030055US1

### U.S. Patent Documents

Examiner Initials	Cite No.	U.S. Patent Document Number	Kind Code	Name of Patentee or Applicant	Publication Date mm-dd-yyyy	Pages, columns, lines where relevant information appears
A/H	A	RE33,949	B2	Mallory, et al.	06-02-1992	↗
	B	2002/0034043	A1	T. Okada, et al.	03-12-2002	
	C	2002/0176214	A1	A. Shukh, et al.	11-28-2002	
	D	2003/0043513	A1	C. Lin	03-06-2003	
	E	4731157	A1	J. Lazzari	03-15-1988	
	F	5196976	A1	J. Lazzari	03-23-1993	
	G	5408373	A1	C. Bajorek	04-18-1959	
	H	5550891	A1	H. Hamilton	08-27-1996	
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### Foreign Patent Documents

Examiner Initials	Cite No.	Foreign Patent Document			Name of Patentee or Applicant	Publication Date mm-dd-yyyy	Pages, columns, lines where relevant information appears
		Off.	Number	Kind Code			

Examiner Signature

A. Heinz

Date Considered

4/12/05

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## OTHER PRIOR ART - NON-PATENT LITERATURE

Examiner Initials	Cite No.	Citation: Author (in capital letters), title, book, symposium, etc.	T
<i>SH</i>	AA	M.Mallory, et al. "One Terabit per Square Inch Perpendicular Recording Conceptual Design," IEEE Transactions on Magnetics, vol. 38, no. 4, July 2002, pp. 1719ff.	
	BB		
	CC		
	DD		

Examiner Signature	<i>A. Heinz</i>	Date Considered	<i>1/19/05</i>
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**Information Disclosure  
Statement by Applicant**By Fax to  
703-872-9306

Application Number: 10/675046  
 Filing Date: 09-29-03  
 First Named Inventor Hsu  
 Group Art Unit 2652  
 Examiner NA  
 Atty. Docket Num. HSJ920030055US1

**U.S. Patent Documents**

Examiner Initials	Cite No.	U.S. Patent Document Number Kind Code	Name of Patentee or Applicant	Publication Date mm-yyyy	Pages, columns, lines where relevant information appears
SM	A	2003/0117749 B1	Shukh, Alexander M.; et al.	June 26, 2003	
	B	20030227714 B1	Parker, Gregory John; et al.	December 11, 2003	
	C	20020036871 B1	Yano, Koji; et al.	March 28, 2002	
	D	20020170165 B1	Plumer, Martin L.; et al.	November 21, 2002	
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**Foreign Patent Documents**

Examiner Initials	Cite No.	Foreign Patent Document			Name of Patentee or Applicant	Publication Date mm-dd-yyyy	Pages, columns, lines where relevant information appears
		Off.	Number	Kind Code			
	J1						
	J2						

Examiner Signature	<i>A. Heinz</i>	Date Considered	<i>4/19/05</i>
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